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(12) **United States Design Patent**
Zhan et al.

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(45) **Date of Patent:** **** Jun. 1, 2021**

(54) **INSPECTION SYSTEM**

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- (**) Term: **15 Years**
- (21) Appl. No.: **29/690,205**
- (22) Filed: **May 6, 2019**
- (51) **LOC (13) Cl.** **10-04**
- (52) **U.S. Cl.**
USPC **D10/46; D10/75; D10/81; D10/102; D24/186**
- (58) **Field of Classification Search**
USPC D10/46, 49, 75, 81, 102; D13/163; D14/302, 307, 388, 900, 902; D24/185, D24/186, 232, 233, 234
CPC G01N 21/95684; G01N 21/95607
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

D556,914 S	*	12/2007	Okamoto	D24/233
D775,365 S	*	12/2016	Mathers	D24/232
D834,724 S	*	11/2018	Mathers	D24/232
D888,705 S	*	6/2020	Saito	D14/307
D909,605 S	*	2/2021	Mathers	D24/232

OTHER PUBLICATIONS

“High Performance X-Ray Inspection Solution”, Baker Hughes a GE Company, Inspection Technologies, Sales Brochure—Micromex and Nanomex, 2019, 1-8.
 Electronics Testing Solutions—NDT for Semiconductors, PCBs and More, High-performance premium nanofocus and microfocus inspection for electronics., <https://www.bakerhughesds.com/industrial-x-ray-ct-scanners/phoenix-micromex-neo-nanomex-neo>, Waygate Technologies, 2021.

* cited by examiner

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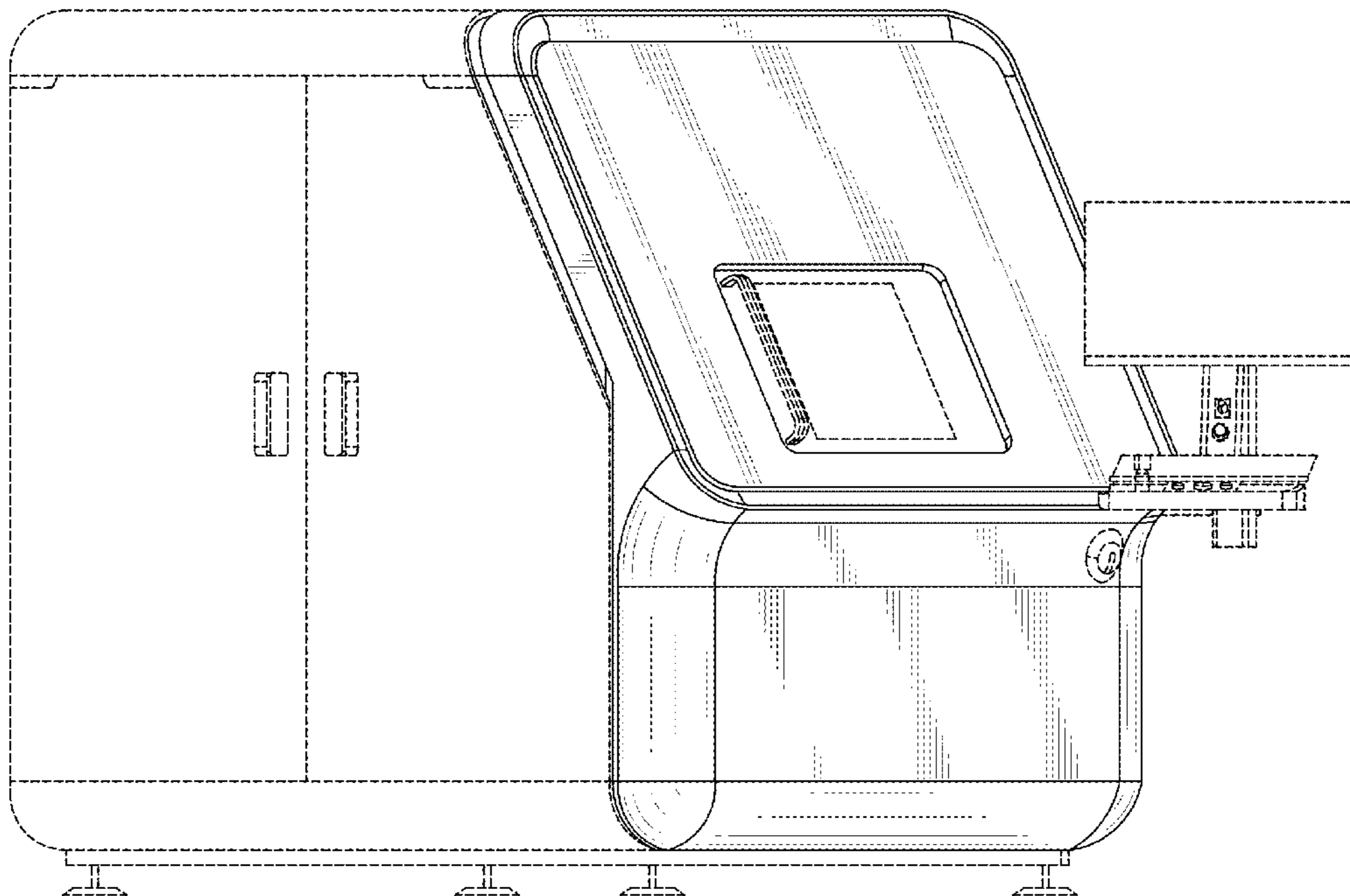
(57) **CLAIM**

The ornamental design for an inspection system, as shown and described.

DESCRIPTION

FIG. 1 is a front view of an inspection system;
 FIG. 2 is a side view thereof;
 FIG. 3 is another side view thereof;
 FIG. 4 is a top view thereof;
 FIG. 5 is a bottom view thereof;
 FIG. 6 is a front perspective view thereof;
 FIG. 7 is a back perspective view thereof; and,
 FIG. 8 is another front perspective view thereof.
 The broken line illustration of portions of the inspection system in the drawing is for illustrative purposes and is not part of the claimed design.

1 Claim, 8 Drawing Sheets



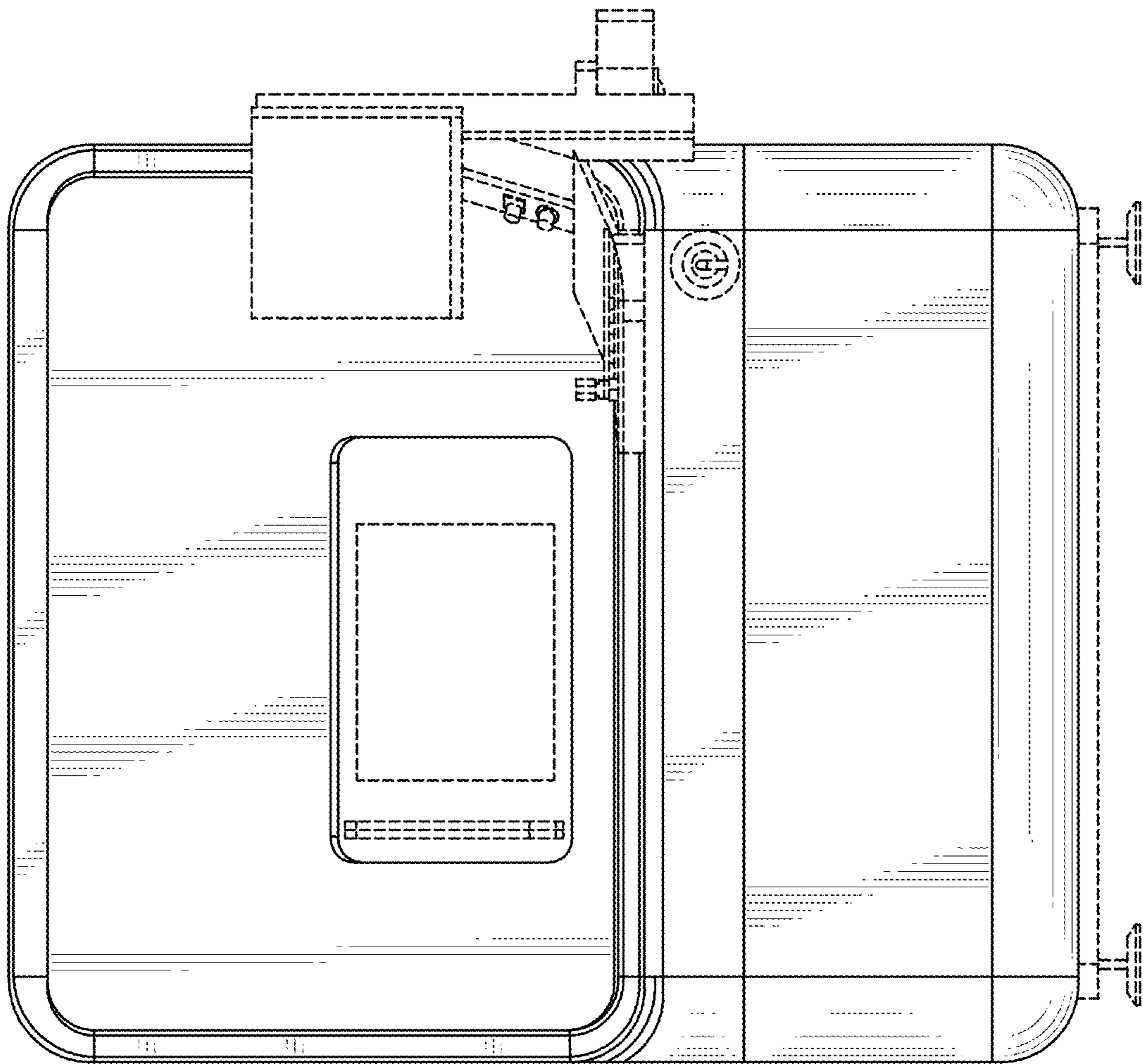


FIG. 1

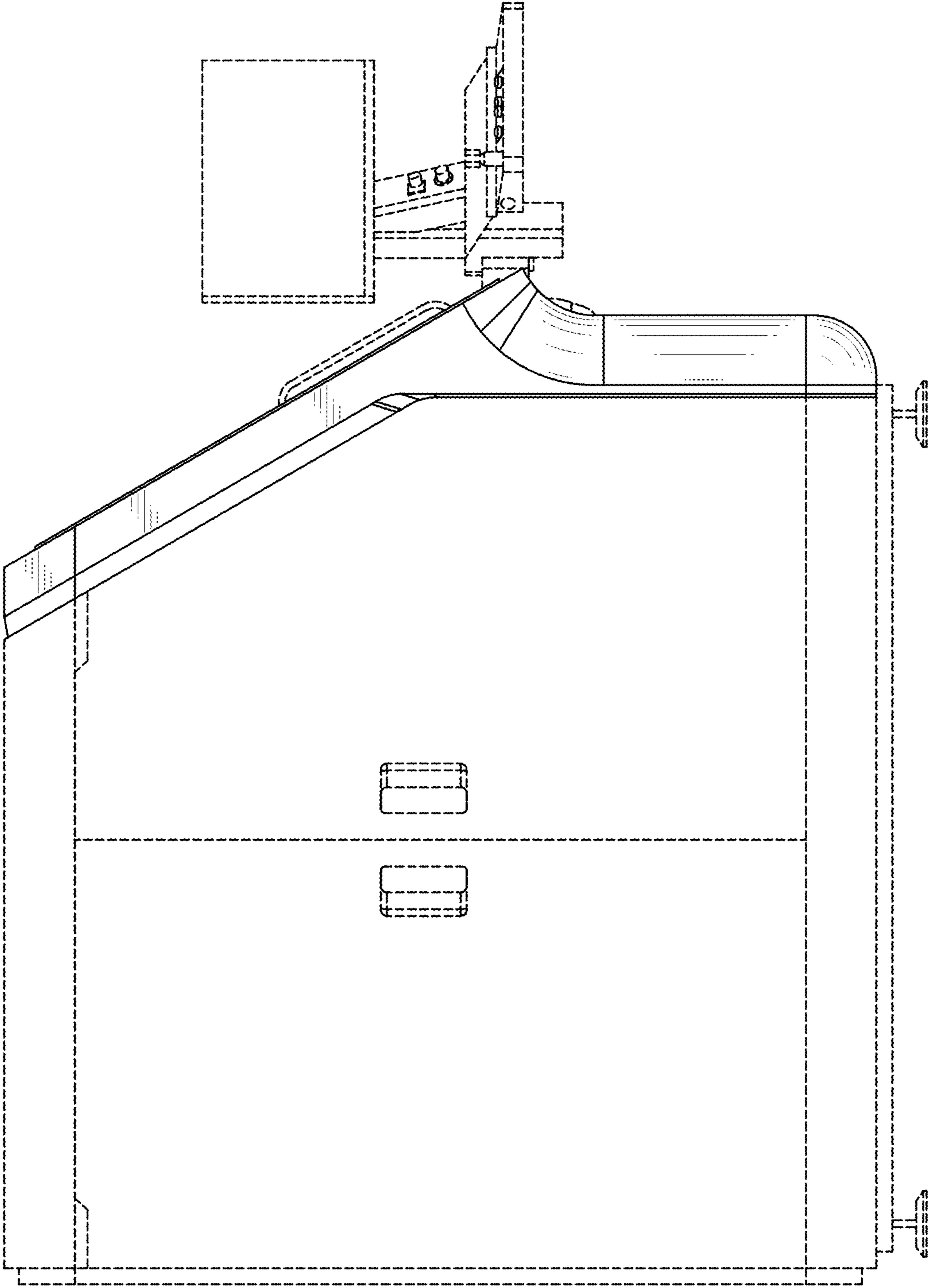


FIG. 2

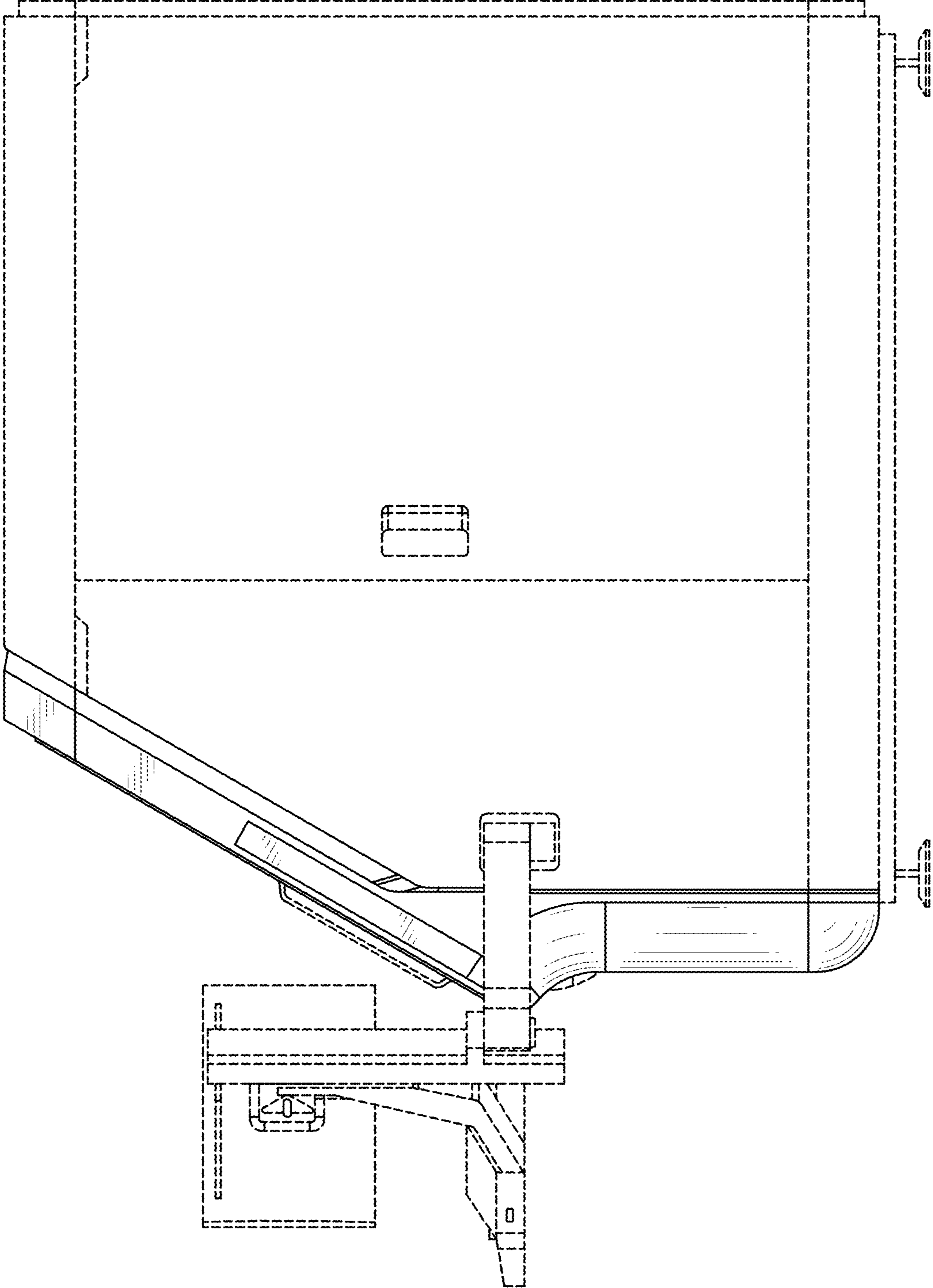


FIG. 3

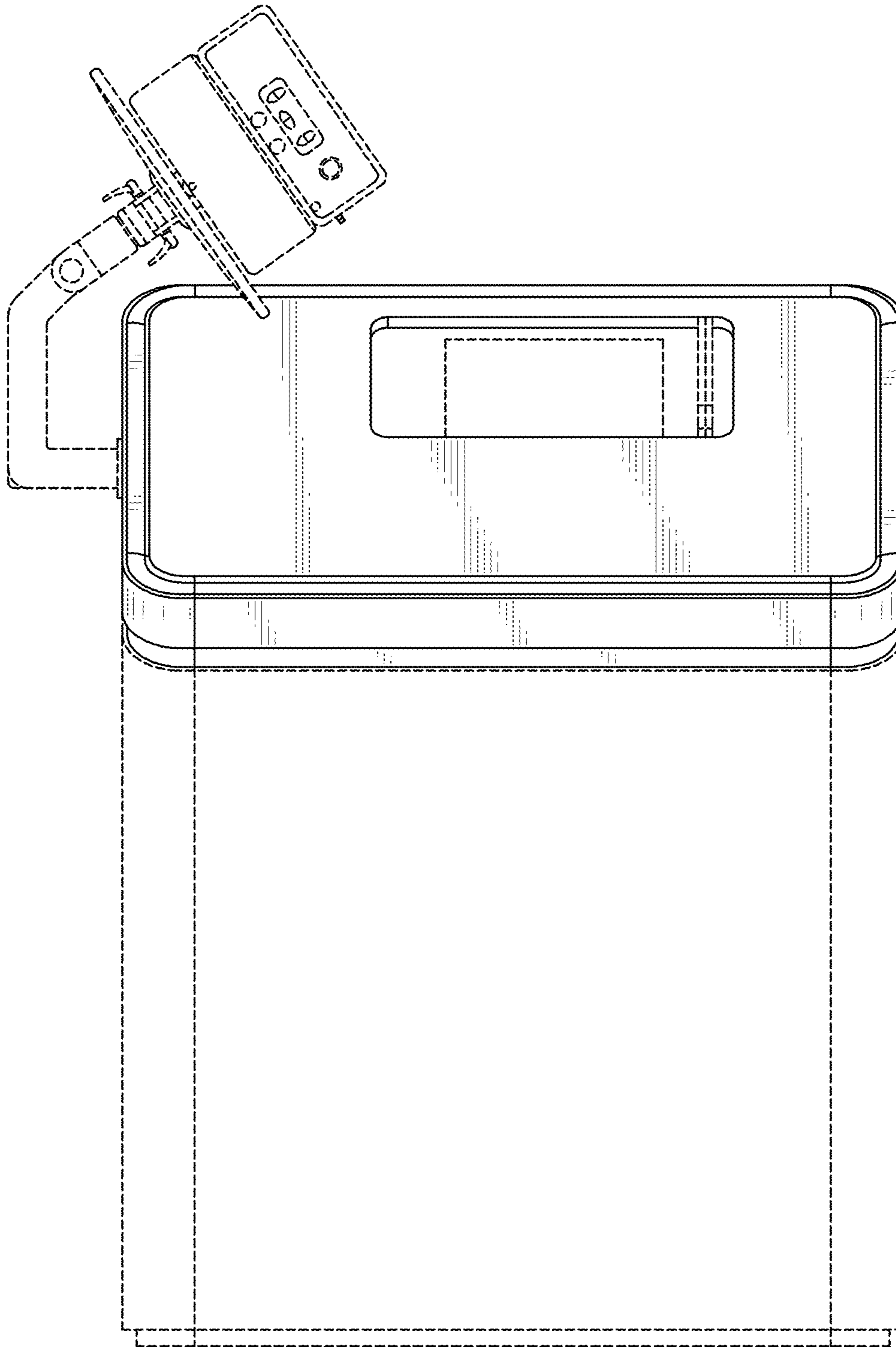


FIG. 4

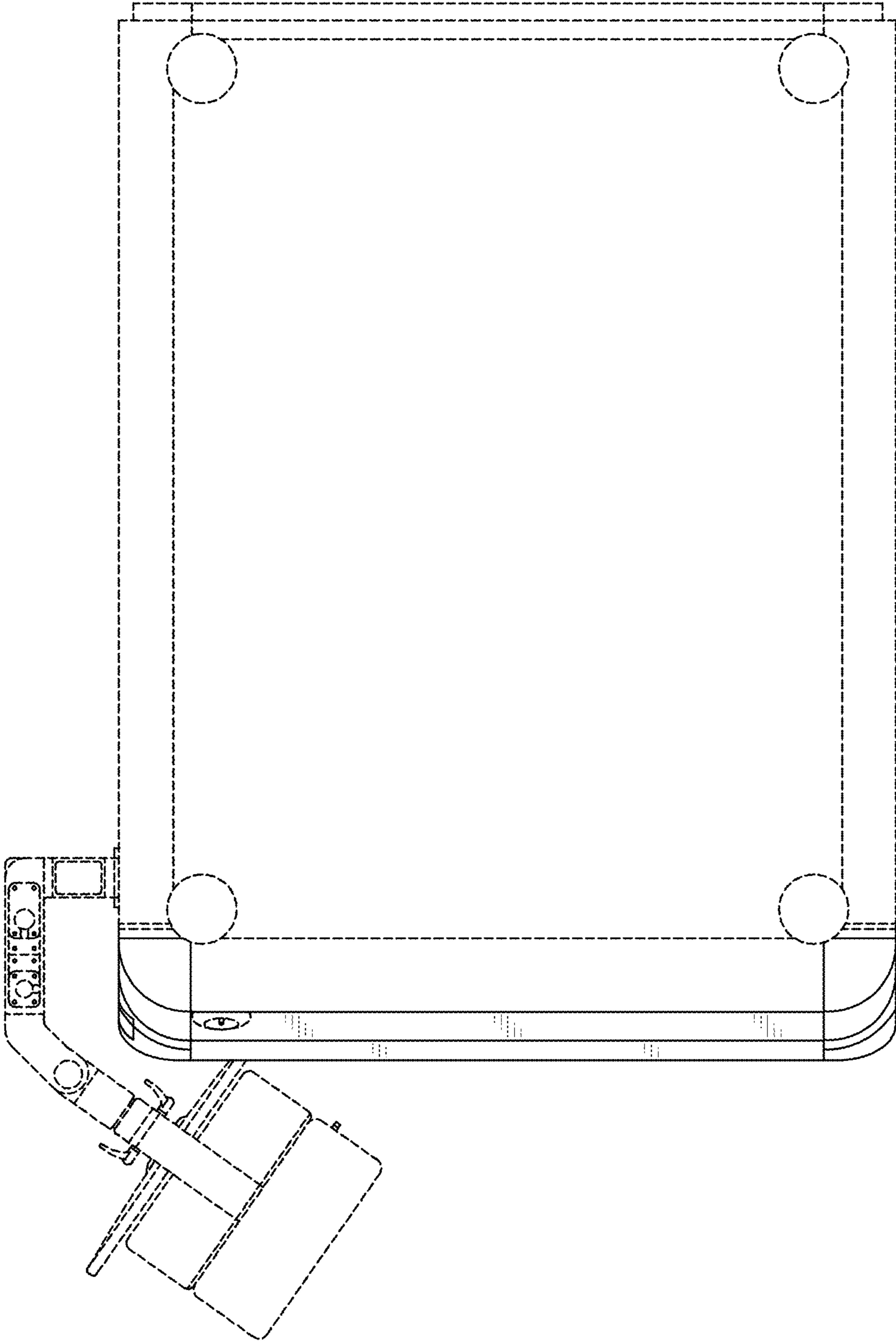


FIG. 5

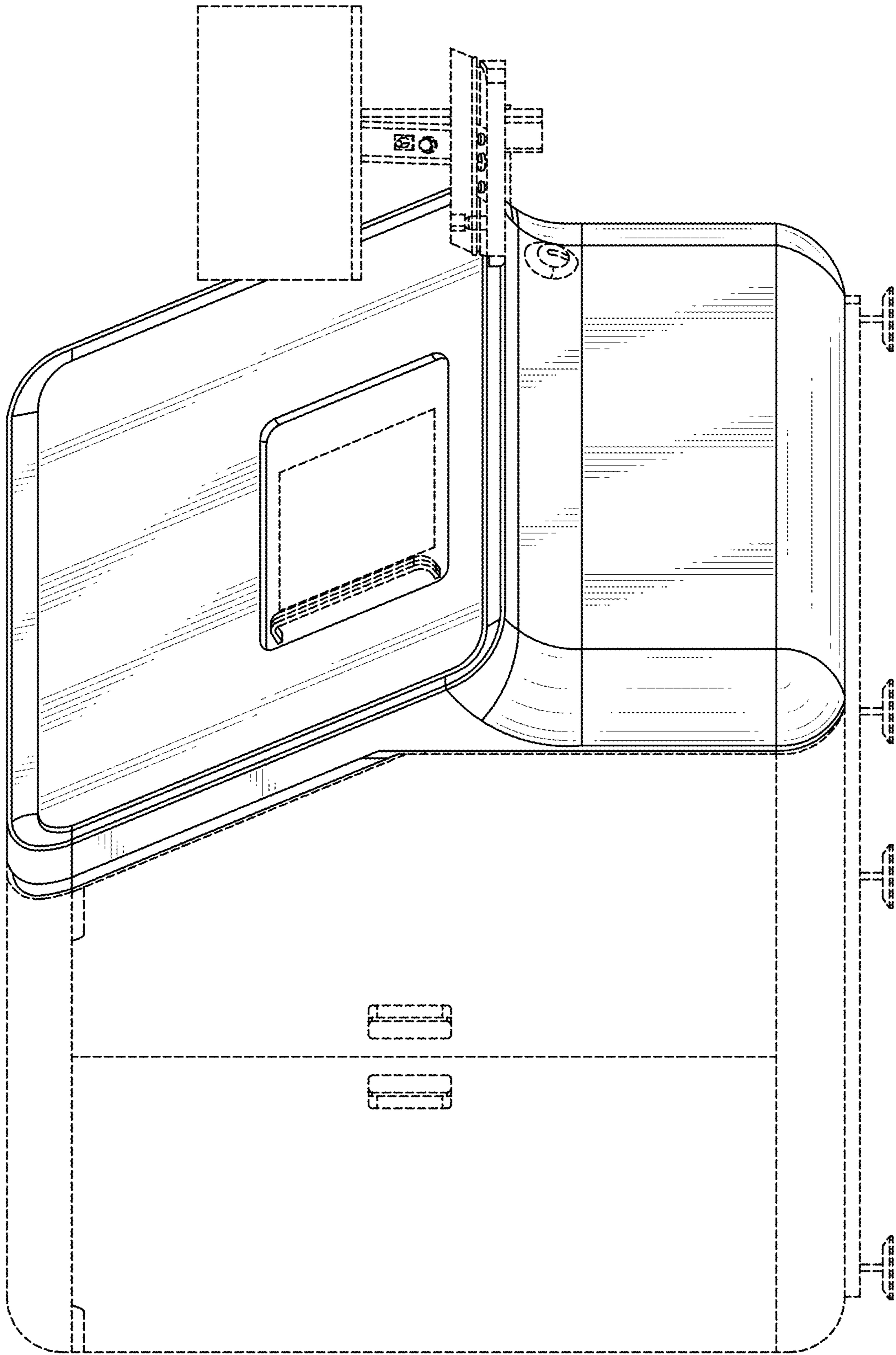


FIG. 6

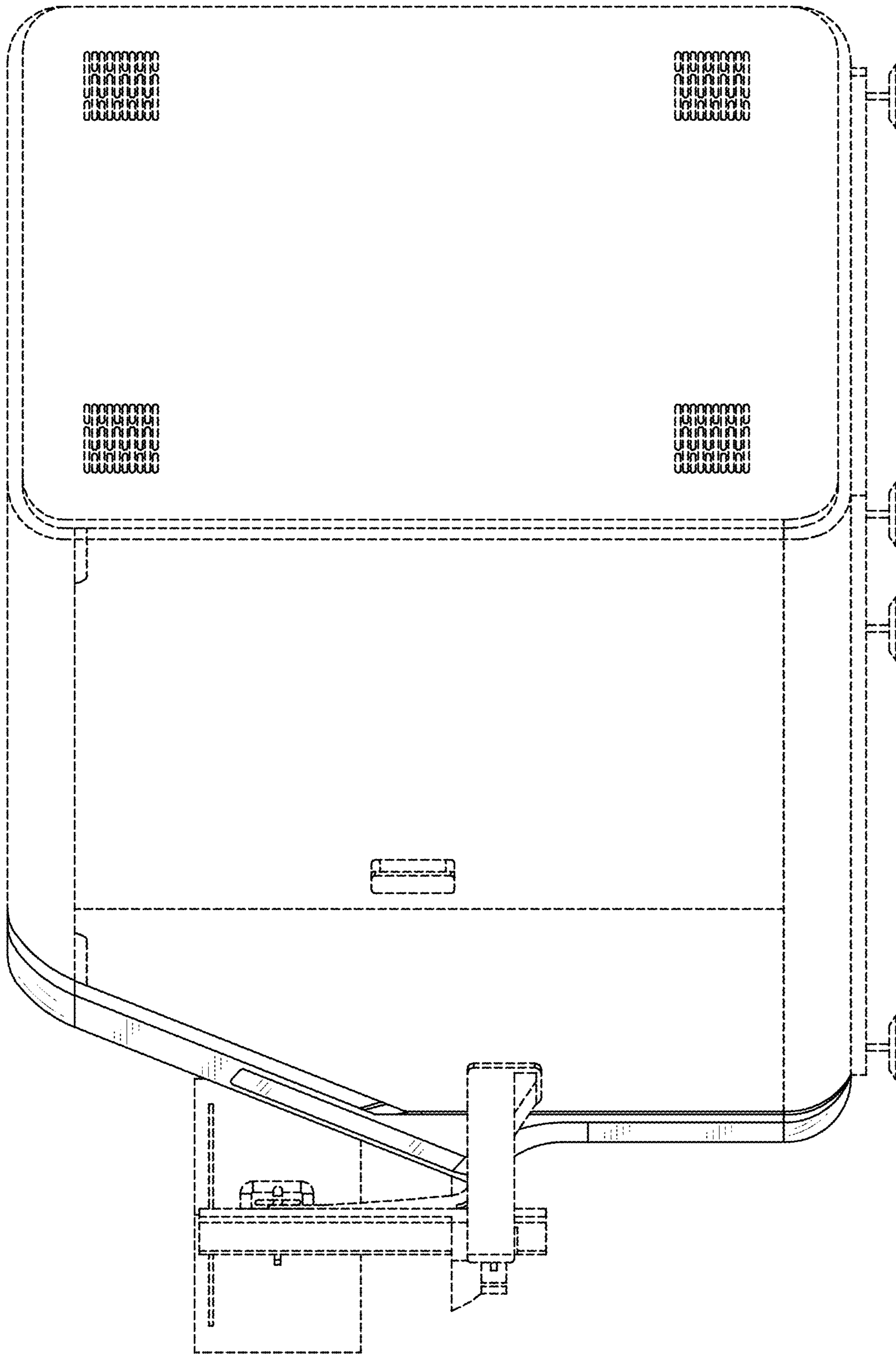


FIG. 7

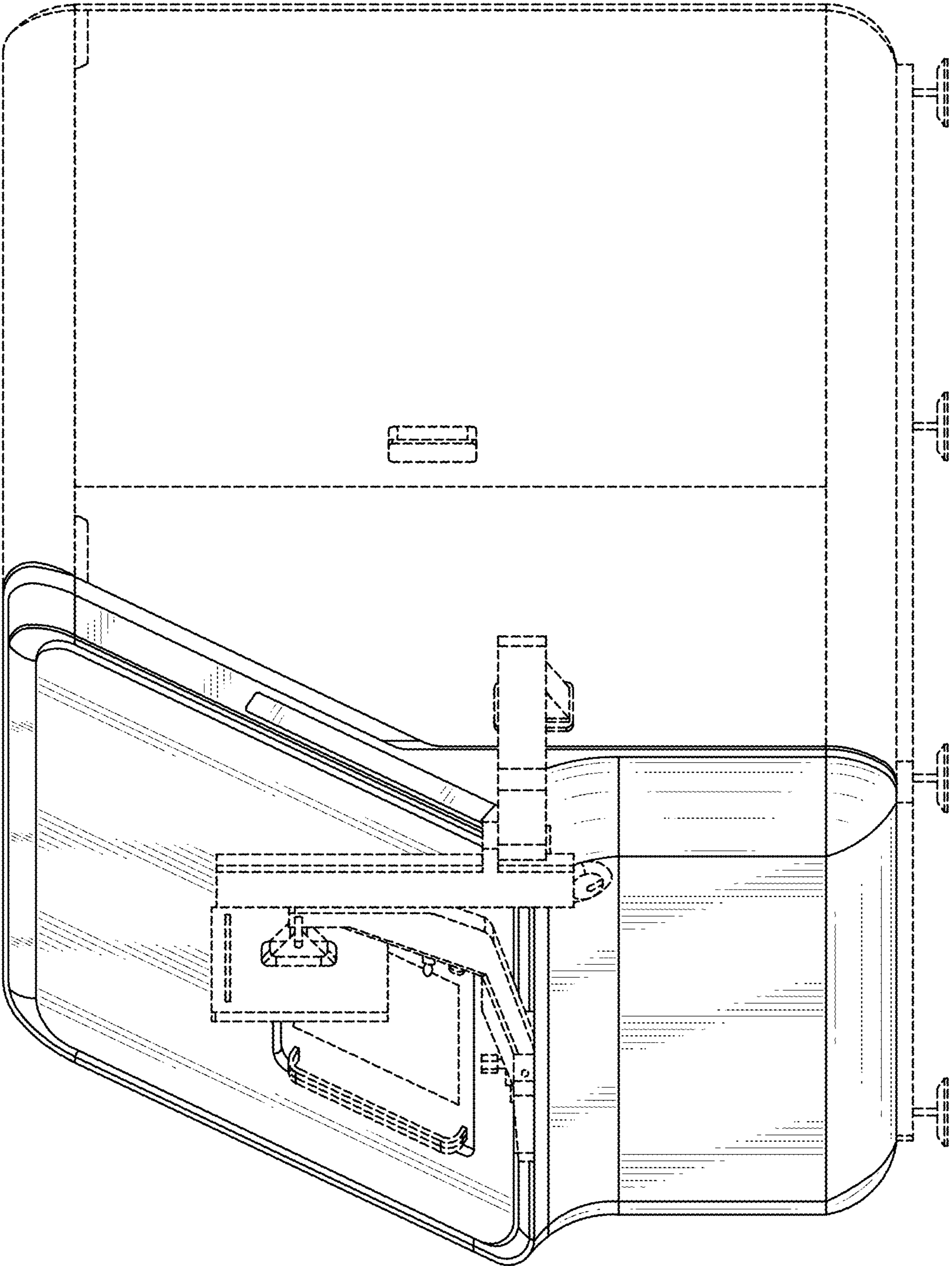


FIG. 8